



# PRODUCT / PROCESS CHANGE NOTIFICATION

PCN-000710

Date: 12-16-2021

P1/9

Semtech Corporation, 200 Flynn Road, Camarillo CA 93012

## Change Details

Part Number(s) Affected:

TS30011-M033QFNR;  
TS30011-M050QFNR;  
TS30011-M000QFNR;

Customer Part Number(s) Affected:  N/A

## Description, Purpose and Effect of Change:

Additional Source to Support Production Assembly and Final Test from Carsem Suzhou to Carsem Malaysia

Change Classification	<input checked="" type="checkbox"/> Major <input type="checkbox"/> Minor	Impact to Form, Fit, Function	<input type="checkbox"/> Yes <input checked="" type="checkbox"/> No
Impact to Data Sheet	<input type="checkbox"/> Yes <input checked="" type="checkbox"/> No	New Revision or Date	<input checked="" type="checkbox"/> N/A

## Impact to Performance, Characteristics or Reliability:

No Impact to performance , Characteristics or Reliability

Implementation Date	12/16/2021	Work Week	WW51
Last Time Ship (LTS) Of unchanged product	N/A	Affecting Lot No. / Serial No. (SN)	N/A
Sample Availability	-	Qualification Report Availability	Yes

## Supporting Documents for Change Validation/Attachments:

- TS30011-M0XXQFNR SZ to Ipoh test qual data Transfer
- TS30011-M0XXQFNR SZ to Ipoh assembly qual data Transfer

## Issuing Authority

Semtech Business Unit:	Power Management	
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FOR FURTHER INFORMATION & WORLDWIDE SALES COVERAGE: <http://www.semtech.com/contact/index.html#support>



**Site Transfer**  
**P/N TS3001X-M0XXQFNR**  
From: Carsem Suzhou  
To: Carsem Ipoh







**COMPARISON BETWEEN CARSEM SUZHOU & CARSEM IPOH**

ITEM	CARSEM SUZHOU	CARSEM IPOH
ATE Tester	ETS364	ETS364
Handler	Manufatcurer : SRM Model : XD248 Type : Turret/Rotary # Sites : Quad	Manufatcurer : SRM Model : XD248 Type : Turret/Rotary # Sites : Quad
Load Board	TS3001X/3004X	TS3001X/3004X
Test Program	ef3001100_BC_10 ef3001115_BC_10 ef3001118_BC_10 ef3001125_BC_10 ef3001133_BC_10 ef3001150_BC_10 ef30011_BC_11	ef3001100_BC_10 ef3001115_BC_10 ef3001118_BC_10 ef3001125_BC_10 ef3001133_BC_10 ef3001150_BC_10 ef30011_BC_11



## SZ vs IPOH Handler Comparison





	Carsem Ipoh	Carsem SZ		IPOH - S248	SZ - XD248	
Model	S248	XD248	Handler Photo			
Manufacturer	SRM Integration (Malaysia) Sdn Bhd	SRM Integration (Malaysia) Sdn Bhd		GUI		
No of Site	Quad	Quad				
Top Marking & Orientation Vision	Yes	Yes				
Coplanarity & Pad Smear Vision	Yes	Yes				
Integrated Tape and Reel	Yes	Yes				
In Pocket Vision	Yes	Yes				
Socket Cleaning Frequency	1x/Shift	1x/Shift				
Impact to Part Lifetime	None	None				


Remarks: Both Carsem SZ and Carsem IPOH handlers are compatible with similar capabilities

## TS3001X Series – Qual Data




Description	Acceptance Criteria	Remarks	Data
<b>Test Repeatability:</b> - 3-5 Devices loop run 30 times;	Pass or Fail 100% match	<b>PASS</b> Done. 10 Units 33X – PASS Consistently. Data as in attached file.	 CDR_UNIT_10OP231.zip

Description	Acceptance Criteria	Remarks	Data
<b>Bin-to-Bin Correlation:</b> - Good and rejects bins are sorted according to the Bin assignment	100% Bin-to-Bin correlation for all good and reject units - Pass/fail correlation;	<b>PASS</b> Done. Attached is the data and summary. All samplings are matching for Bin to Bin Summary vs Physical	 Bin to Bin Correlation

Description	Acceptance Criteria	Remarks	Data
<b>QA gate validation:</b> -Good units to be tested 100% at QA gate after these lots have been processed through final production test flow.	No QA Gate failures.	<b>PASS</b> Done. Attached is the data and summary. All 100% Inline QA sampling test is PASS	 QA Summary

## TS3001X Series – Qual Data



Description	Acceptance Criteria	Remarks	Data
<b>Tester-to-tester variation: GR&amp;R</b> - Perform tester to tester variation analysis for selected parameters; - Tester 1, Tester 2; - DIB1, DIB2; - Test site 1 to test site n;	Tester-to-Tester variation (GR&R) for selected parameters: - GRR<=10% Acceptable; - GRR<=33% Waiver required; - GRR >33% reject;	<b>PASS</b> Done. All within spec. Using Site1 and Site 2 from same tester.	 TS3001X GRNR

Test#	Test Name	Unit	Sample	In Spec	Max Spec	Average Min	Average Max	Average Mean	StDev	Max-AveMin	Min-AveMax	Mean - Mean	Mean + Mean	Repeatability	Reproducibility	R&R	% R&R	Remarks
10000101	lim_meas_val	AMPS	30	1.50	2.000	1.801	1.807	1.804	0.006	1	1	0.242	0.000	0.242	0.000	0.242	48.4%	Leakage Test. Baseline issue. Test is capable with cpk > 1.33
10000101	osc_meas_val	KHERTZ	30	960.00	1050.000	997.984	998.820	998.902	0.036	1	1	43.059	0.000	43.059	0.000	43.059	47.0%	High frequency. Baseline issue. Test is capable with cpk > 1.33
10100411	in_val	VOLTS	30	3.90	4.700	4.452	4.454	4.453	0.002	1	1	0.383	0.000	0.383	0.000	0.383	37.9%	Vout Measurement. Baseline issue. Test is capable with cpk > 1.33
100070101	ovuv_meas_val	%	30	88.00	102.000	100.972	100.964	100.976	0.012	1	1	1.175	0.000	1.175	0.000	1.175	26.4%	Several factors affecting %R&R > 10% that can be attributed to ATE
20100414	en_leak_ov_delta	uAIPS	30	-3.00	3.000	-1.068	-1.068	-1.063	0.019	1	1	1.865	0.000	1.865	0.000	1.865	27.8%	Capability. some noise
10100410	en_leak_ov	uAIPS	30	-3.00	3.000	-1.008	-1.008	-1.007	0.002	1	1	1.948	0.000	1.948	0.000	1.948	26.5%	Differences on testboards, cables, sockets, interface boards, etc. These tests have historically high %R&R > 18% since day 1 in Carsem SZ. These tests do not impact FT yield since the tests are capable with cpk > 1.33. Test distribution between Carsem SZ and Carsem IPOH are comparable
20100413	en_leak_ov_delta	uAIPS	30	-0.10	0.100	-0.017	-0.017	-0.014	0.007	1	1	0.843	0.000	0.843	0.000	0.843	21.6%	
100140103	vout_meas	VOLTS	30	3.25	3.346	3.299	3.300	3.300	0.001	1	1	0.018	0.000	0.018	0.000	0.018	19.6%	
100010121	bg_tc_eff	mVOLTS	30	-10.00	10.000	0.334	0.788	0.521	0.374	1	1	3.757	0.000	3.757	0.000	3.757	18.6%	
20100416	PG_authorized_leak_delta	nAIPS	30	-30.00	30.000	0.575	2.822	1.899	2.247	1	1	10.293	3.196	10.293	3.196	10.778	18.0%	
10100412	en_resist	uAIPS	30	88.00	245.000	169.346	169.517	169.433	0.179	1	1	28.005	0.000	28.005	0.000	28.005	17.6%	
10100409	en_leak_ov	uAIPS	30	-1.00	0.000	-1.424	-1.427	-1.415	0.018	1	1	0.313	0.000	0.313	0.000	0.313	12.0%	
20100407	en_leak_ov_posit	uAIPS	30	-2.00	1.000	-1.414	-1.389	-1.422	0.024	1	1	0.318	0.000	0.318	0.000	0.318	10.5%	
10104040	pg_eff_&_js	nAIPS	30	-25.00	28.000	17.283	24.961	20.907	7.387	1	1	19.304	11.528	19.304	11.528	22.552	18.0%	

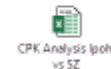
## TS3001X – Carsem Ipoh Qual Data



### CPK Carsem SZ VS Carsem Ipoh - Summary

High Capacity Analysis Data														30 Samples Production Data														
Test Number	Test Name	Mean	Std Dev	Min	Max	%	Spec Limit	Spec High	Std %	% Spec	Yield	Pre Def Item	Cap	Test Number	Test Name	Mean	Std Dev	Min	Max	%	Spec Limit	Spec High	Std %	% Spec	Yield	Pre Def Item	Cap	
100010102	bg_tc_eff	0.607	0.07	0.537	0.677	0	0.7	0.887	0.00	0	0.619	100	0	10010102	bg_tc_eff	0.603	0.07	0.537	0.677	0	0.7	0.887	0.00	0	0.619	100	0	
100030100	en_leak_ov	0	0	0	0	0	0	0	0	0	0	0	0	100030100	en_leak_ov	0	0	0	0	0	0	0	0	0	0	0	0	0
100140103	vout_meas	3.299	0.001	3.299	3.300	0	3.1	3.300	0	0.995	100	0	0.995	100140103	vout_meas	3.299	0.001	3.299	3.300	0	3.1	3.300	0	0.995	100	0	0.995	
100010121	bg_tc_eff	0.521	0.374	0.147	2.095	0	0	0.887	0	0.308	100	0	0.308	100010121	bg_tc_eff	0.521	0.374	0.147	2.095	0	0	0.887	0	0.308	100	0	0.308	
100010121	bg_tc_eff	0.521	0.374	0.147	2.095	0	0	0.887	0	0.308	100	0	0.308	100010121	bg_tc_eff	0.521	0.374	0.147	2.095	0	0	0.887	0	0.308	100	0	0.308	

Critical Parameter looks good



Conclusion:  
From the Cpk data all parameters are comparable for both Suzhou and Carsem

## TS3001X Series – Qual Data



### SPIKE CHECK

- Spike Check done ETS, while loop testing the device.
- No ripple found and no device damaged during the 1000X loop test.
- All the waveform captured within acceptable range
- Details are in the spike plot check attached.
- Spike check for both Carsem Suzhou and Carsem Ipoh are compatible



## TS3001X Series – Qual Data – Other Summary



- No changes done to the Test Program and Limits:
  - FT Program:** *ef30011XX\_BC\_10 (ECO-053461) – TS30011-MOXXQFNR*  
*& ef30011\_BC\_11 (ef30011\_BC\_11) – TS30012-MOXXQFNR & TS30013-MOXXQFNR*
  - QA Program:** *ef30011XX\_BC\_10 (ECO-053461) – TS30011-MOXXQFNR*  
*& ef30011\_BC\_11 (ef30011\_BC\_11) – TS30012-MOXXQFNR & TS30013-MOXXQFNR*
- Both Carsem Suzhou and Ipoh uses the same Tester Platform (ETS)
- Both Carsem Suzhou and Ipoh uses the same QC flow diagram  
*100% FT and Sample QA.*
- No Changes required in Control Plan and FMEA.



**PCN No. 000710**  
**Qualification of Carsem Ipoh for TS3001X-M0XXQFNR products**

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## Introduction

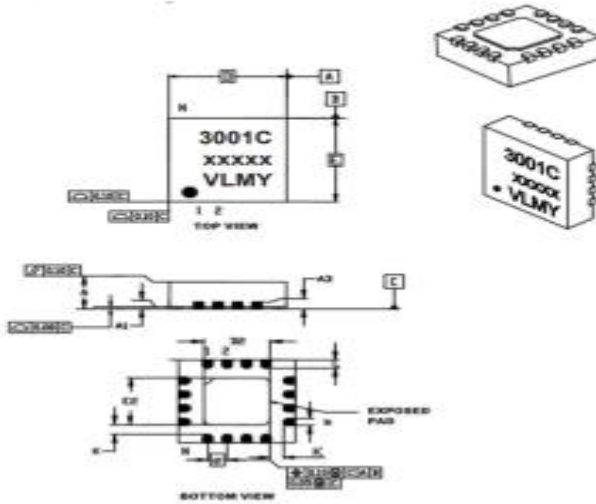


- TS3001X-M0XXQFNR Series have been qualified in Carsem Ipoh, Malaysia as a site for assembly. Current Assembly is performed in Carsem SuZhou, China.
  
- The change affect applicable to products:  
TS3001X-M0XXQFNR
  
- Qualification Vehicles selected are ZSPM4561CI1R
  
- Schedule for Implementation  
Passing REL qualification MSL 1 under Rel job# 7197.

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### SEMTECH Package Outline on TS3001X-M0XXQFNR CarsemSZ (Old) and CarsemIPH (New)



Units	Millimeters			
	MIN	NCM	MAX	
Number of Pins	N	16		
Pitch	e	0.50 BSC		
Overall Height	A	0.80	0.90	1.00
Standoff	A1	0.00	0.02	0.05
Contact Thickness	A3	0.20 REF		
Overall Length	D	3.00 BSC		
Exposed Pad Width	E2	1.55	1.70	1.80
Overall Width	E	3.00 BSC		
Exposed Pad Length	D2	1.55	1.70	1.80
Contact Width	b	0.20	0.25	0.30
Contact Length	L	0.20	0.30	0.40
Contact-to-Exposed Pad	K	0.20	-	-

**No Change in  
Package Outline.**

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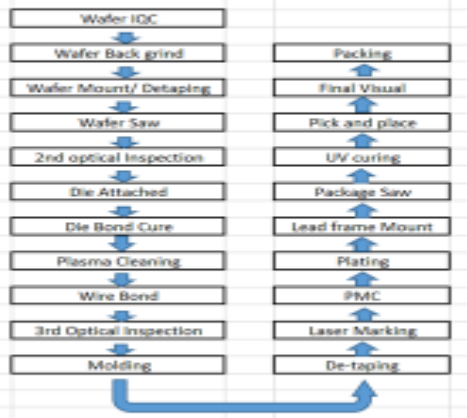
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### Assembly Process Flow Comparison for CarsemSZ (Old) vs. CarsemIPH (New)



Assembly Process Flow:

#### CARSEMSZ (Old)



#### CARSEMIPH (New)



- No major Change in manufacturing Flow for both Assembly site CarsemSZ versus CarsemIPH except additional process step for plasma cleaning before mold for CarsemIPH.

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**BOM Comparison CarsemSZ (Old) vs CarsemIPH (New)**



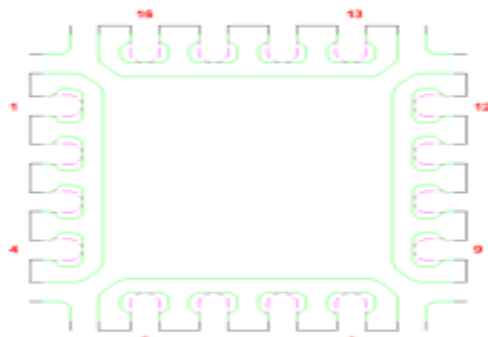
CarsemSZ (Old)				CarsemIPH (New)			
Epoxy	Leadframe	Wire Type	Mold compound	Epoxy	Leadframe	Wire Type	Mold compound
Henkel QMI-519 Conductive epoxy	DCI AgCu LDF	1.2 mils PdCu wire	Sumitomo G770HCD	Henkel QMI-519 Conductive epoxy	DCI AgCu LDF	1.2 mils PdCu wire	Sumitomo G770HCD

- BOM for both supplier CarsemSZ and CarsemIPH are no difference.

**Lead frame outline Comparison CARSEMSZ (OLD) Vs CARSEMIPH(NEW)**



**Lead frame Outline**

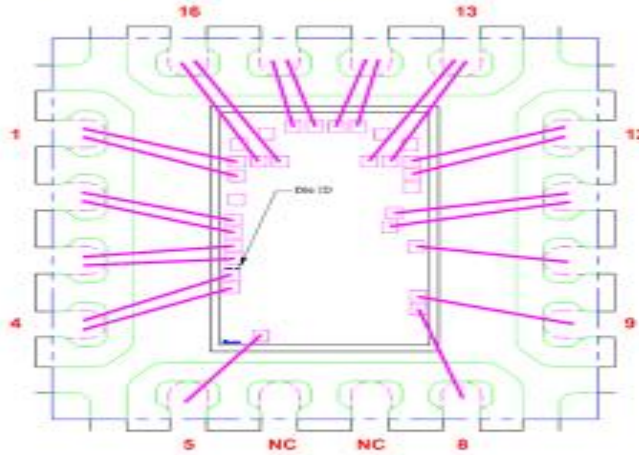


**Die Pad :2.1 x 2.1mm**  
**Exposed Pad : 1.7 x 1.7mm**

**No Difference on lead frame outline for CARSEMSZ and CARSEMIPH as both are using the same lead frame.**



**Bonding Layout (CarsemSZ vs  
CarsemIPH)**



**No Change in Bonding Layout.**